

## **Search Notes**



**Application/Control No.**

10/601,275

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**Examiner**

Dah-Wei D. Yuan

**Applicant(s)/Patent under  
Reexamination**

YE ET AL.

## **Art Unit**

1745

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner